

# Volterus™ High Power Probing Solution

- Manual, Semi & Fully Automatic Versions
- High Voltage to 10 kV
- High Current to 100 A
- Integrated Solutions
- Modular PS4L Hardware & Software Architecture

## SAFETY

- High Voltage protection is accomplished by one of two methods
  - Infrared Light Curtain
  - Dark Box Enclosure

## OPTICS

- Compound Microscope & Camera System
  - Automatic Alignment

## INTERLOCK

- Interlock LED indicator is connected to the test instrument
- Signal is only applied when the system is completely safe to operate

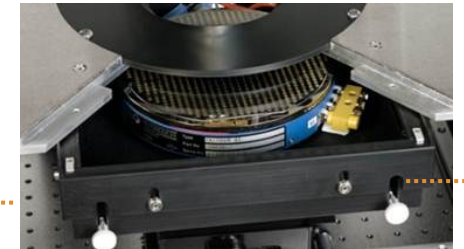
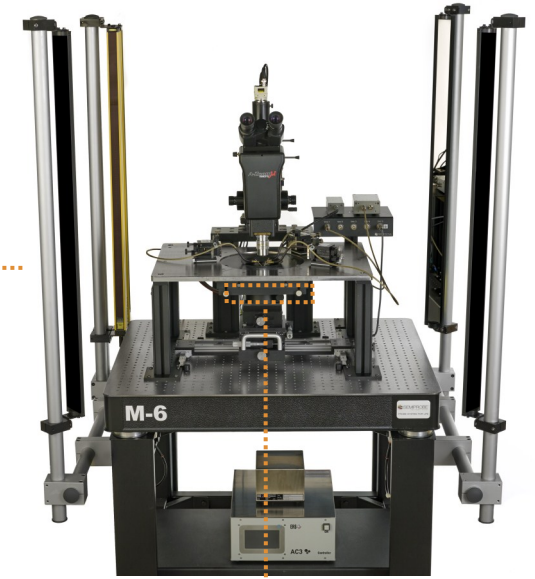
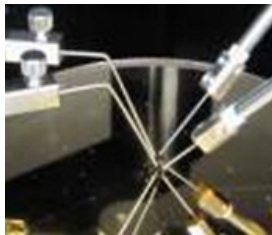
## INTERFACE PANEL

- Interface Panel to the test instrument



## HIGH VOLTAGE PROBES

- High Voltage probe arms contact the device under test (DUT)



## CHAMBERED WAFER CHUCK

- Spring loaded chamber allows for extra protection while allowing Z height manipulation
- Thin wafer handling
- Temperature Range of -65°C to 300°C

## SOFTWARE

- Control system via SemiProbe PILOT Software Suite
- The probe system can either be the Master or slave to the test instrument

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